## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:	)
Noriaki HIRAGA	)
Application No.: Unassigned	) Group Art Unit: Unassigned
Filed: August 18, 2003	) Examiner: Unassigned
For: SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE WITH ENHANCED RESISTANCE TO ELECTROSTATIC BREAKDOWN	) ) ) )

Commissioner for Patents
U.S. Patent and Trademark Office
2011 South Clark Place
Customer Window, MS Patent Application
Crystal Plaza Two, Lobby, Room 1B03
Arlington, VA 22202

## REQUEST FOR APPROVAL OF DRAWING CHANGES

Sir:

Subject to the approval of the Examiner, it is respectfully requested that Figs. 2A, 2B, 4A, 4B, 5A, 5B and 6 be substituted with the corresponding figures of the attached substitute four (4) drawing sheets including seven (7) figures..

It is respectfully submitted that these changes introduce no new matter as they conform to the specification and/or drawings as originally filed, pursuant to 37 C.F.R. §1.81(d).

Respectfully submitted,

MORGAN, LEWIS & BOCKIUS LLP

Date: August 18, 2003

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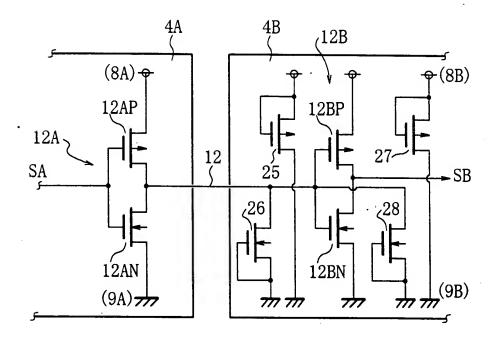


Fig. 2A

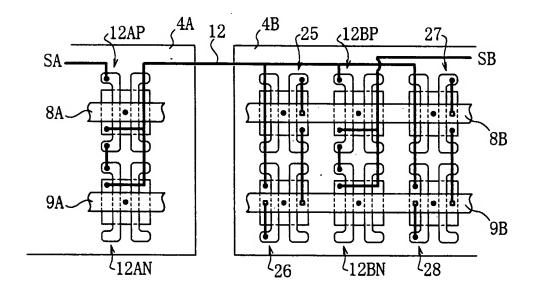


Fig. 2B

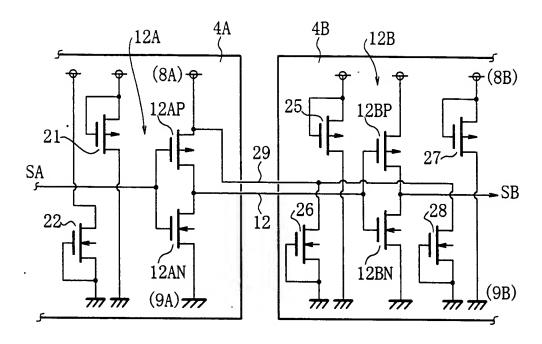


Fig. 4A

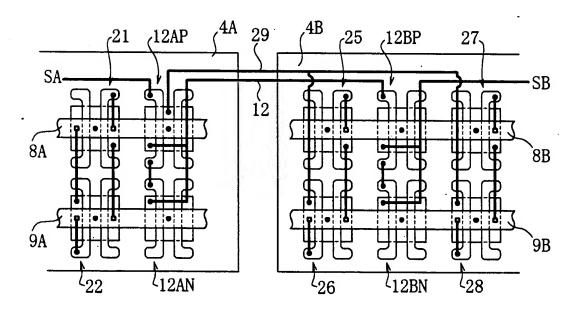


Fig. 4B

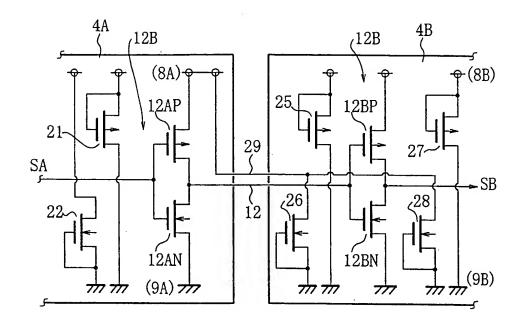


Fig. 5A

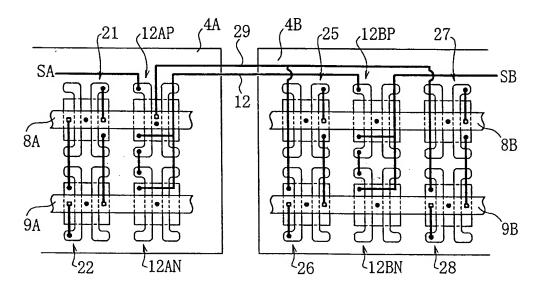


Fig. 5B

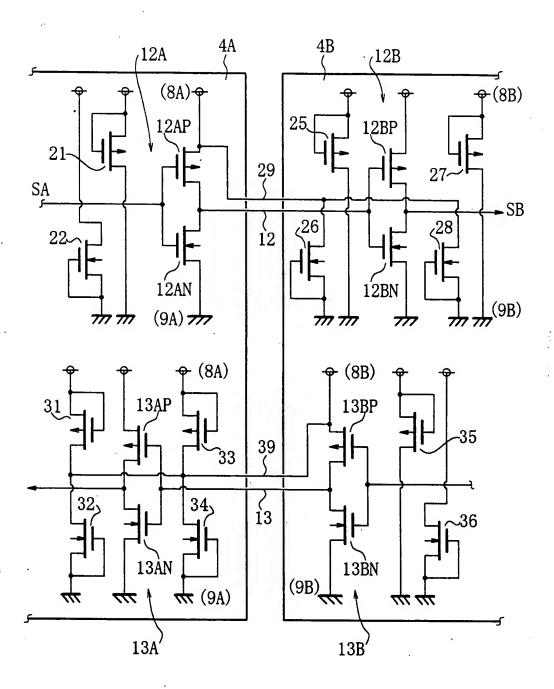


Fig. 6